





































Report No.: OT-189-RWD-027



# 15. FREQUENCY STABILITY / VARIATION OF AMBIENT TEMPERATURE

## 15.1 Operating environment

Temperature : 24 °C

Relative humidity : 47 % R.H.

## 15.2 Test set-up

1. Frequency Stability (Voltage Variation)

+20 °C temperature and  $\pm 15\%$  supply voltage variations. If a product is specified to operate over a range of input voltage then the -15% variation is applied to the lowermost voltage and the +15% is applied to the uppermost voltage.

- (1) Vary primary supply voltage from ±15% of the nominal value for other than hand carried battery equipment.
- (2) For hand carried, battery powered equipment, reduce primary supply voltage to the battery-operating end point which shall be specified by the manufacturer.
- 2. Frequency Stability (Temperature Variation)

Turn EUT off and set chamber temperature to -30 °C and then allow sufficient time (approximately 20 to 30 minutes after chamber reach the assigned temperature) for EUT to stabilize. Turn ON EUT and measure the EUT operating frequency and then turn off the EUT after the measurement. The temperature in the chamber was raised 10 °C step from -30 °C to +50 °C. Repeat above method for frequency measurements every 10 °C step and then record all measured frequencies on each temperature step.

### 15.3 Test equipment used

	Model Number	Manufacturer	Description	Serial Number	Last Cal.
■ -	FSV30	Rohde & Schwarz	Signal Analyzer	101200	Aug. 23, 2018 (1Y)
■ -	AAMCS-UDC	AA-MCS	Directional Coupler	400	Aug. 23, 2018 (1Y)
■ -	MT8821C	ANRITSU	Radio Communication Analyzer	6261849029	Aug. 22, 2018 (1Y)
■	PSL-2KP	ESPEC	Environmental Test Chamber	14009407	Feb. 23, 2018 (1Y)
<b>I</b> -	PWS-3003D	Protek	DC Power Supply	4020409	Aug. 24, 2018 (1Y)

All test equipment used is calibrated on a regular basis.

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EMC-003 (Rev.2)



### 15.4 Test data

15.4.1 Test data for Voltage(V)\_LTE Band 4

Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM
	12.0		1 732 500 017	0.009 8
20	10.2	1 732 500 000	1 732 500 015	0.008 7
	13.8		1 732 500 019	0.011 0

15.4.2 Test data for Temperature( ° C) \_LTE Band 4

Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM
-30			1 732 499 989	-0.006 3
-20			1 732 499 986	-0.008 1
-10			1 732 499 983	-0.009 8
0	12.0 V		1 732 499 993	-0.004 0
10		1 732 500 000	1 732 500 011	0.006 3
20			1 732 500 017	0.009 8
30			1 732 500 021	0.012 1
40			1 732 500 019	0.011 0
50			1 732 500 023	0.013 3

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15.4.3 Test data for Voltage(V)\_LTE Band 12

Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM
	12.0		707 500 016	0.022 6
20	10.2	707 500 000	707 500 014	0.019 8
	13.8		707 500 018	0.025 4

15.4.4 Test data for Temperature( ° C) \_LTE Band 12

Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM
-30			707 499 986	-0.019 8
-20			707 499 988	-0.017 0
-10			707 499 993	-0.009 9
0		707 500 000	707 499 997	-0.004 2
10	12.0 V		707 500 008	0.011 3
20			707 500 016	0.022 6
30			707 500 019	0.026 9
40			707 500 014	0.019 8
50			707 500 012	0.017 0

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15.4.5 Test data for Voltage(V)_LTE Band 13						
Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM		
	12.0		781 999 987	-0.016 6		
20	10.2	782 000 000	781 999 985	-0.019 2		
	13.8		781 999 988	-0.015.3		

15.4.6 Test data for Temperature( ° C) \_LTE Band 13

Temperature( ° C)	Power(VDC)	Center Freq.	Measured Freq.	PPM
-30			781 999 984	-0.020 5
-20			781 999 987	-0.016 6
-10			781 999 982	-0.023 0
0			782 000 006	0.007 7
10	12.0 V	782 000 000	781 999 998	-0.002 6
20			781 999 997	-0.003 8
30			781 999 992	-0.010 2
40			781 999 994	-0.007 7
50			781 999 996	-0.005 1

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